

Search Notes



Application/Control No.

10/650,430

Examiner

Justin Knapp

Applicant(s)/Patent under
Reexamination

CHEN, CHIH-WEI

Art Unit

2182

SEARCHED

Class	Subclass	Date	Examiner
710	36	4/6/05	
↓	19	↓	↓
↓	301	↓	↓
↓	302	↓	↓
↓	72	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST search	4/6/05	